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| Search Notes | Application/Control No. | Applicant(s)/Patent Under Reexamination |
|  | 10588369 | BANIN ET AL. |
| | Examiner | Art Unit |
| | John P Dulka | 2895 |

SEARCHED

| Class | Subclass | Date | Examiner |
|--------------|-----------------|-------------|-----------------|
| 257 | 288 | 2/26/2009 | JPD |
| 257 | 497 | 2/26/2009 | JPD |
| 257 | 009 | 2/26/2009 | JPD |

SEARCH NOTES

| Search Notes | Date | Examiner |
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| East author search (US Patent / US PGPUB / DERWENT / IBM_TDB / EPO / JPO / FPRS) | 2/26/2009 | JPD |
| East number search (US Patent / US PGPUB / Derwent / IBM_TDB / EPO /JPO / FPRS) | 10/21/2009 | JPD |
| East tagged search (US Patent / US PGPUB / Derwent / IBM_TDB / EPO /JPO / FPRS) | 6/17/2011 | JPD |
| East forward/back search (US Patent / US PGPUB / Derwent / IBM_TDB / EPO /JPO / FPRS) | 6/17/2011 | JPD |

INTERFERENCE SEARCH

| Class | Subclass | Date | Examiner |
|--------------|-----------------|-------------|-----------------|
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/J.P.D./
Examiner.Art Unit 2895